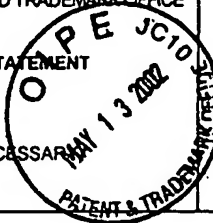


FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASMEX.328A	APPLICATION NO. 10/074,633
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT Michael A. Todd	
(USE SEVERAL SHEETS IF NECESSARY)		FILING DATE February 11, 2002	GROUP 2812



U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
LP	4,363,828	12/14/82	Brodsky et al.				
	4,495,218	1/22/85	Azuma et al.				
	4,585,671	4/29/86	Kitagawa et al.				
	4,684,542	8/4/87	Jasinski et al.				
	5,227,329	7/13/93	Kobayashi et al.				
	5,607,724	3/4/97	Beinglass et al.				
	5,614,257	3/25/97	Beinglass et al.				
	5,648,293	7/15/97	Hayama et al.				
	5,656,531	8/12/97	Thakur et al.				
	5,695,819	12/9/97	Beinglass et al.				
	5,700,520	12/23/97	Beinglass et al.				
	5,786,027	7/28/98	Rolfson				
	5,789,030	8/4/98	Rolfson				
	5,837,580	11/17/98	Thakur et al.				
	5,874,129	2/23/99	Beinglass et al.				
	5,876,797	3/2/99	Beinglass et al.				
	5,885,869	3/23/99	Turner et al.				
	6,027,705	2/22/00	Kitsuno et al.				11/30/98
	6,083,810	7/4/00	Obeng et al.				12/5/98
	6,197,694 B1	3/8/01	Beinglass				7/31/98

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
LP	57209810 A	12/23/82	Japan			Abstract	
J	59078918 A	5/8/84	Japan			Abstract	
J	59078919 A	5/8/84	Japan			Abstract	

EXAMINER	LONG PHAM	DATE CONSIDERED	9/12/04
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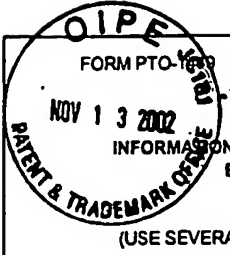
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT Michael A. Todd	
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FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
LP		60043485 A	3/8/85	Japan			Abstract	
		61153277 A	7/11/86	Japan			Abstract	
		62076612 A	4/8/87	Japan			Abstract	
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		01217956 A	8/31/89	Japan			Abstract	
		01268064 A	10/25/89	Japan			Abstract	
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		03185817 A	8/13/91	Japan			Abstract	
		03187215 A	8/15/91	Japan			Abstract	
		03292741 A	12/24/91	Japan			Abstract	
		04323834 A	11/13/92	Japan			Abstract	
		05021378 A	1/29/93	Japan			Abstract	
		05062911 A	3/12/93	Japan			Abstract	
		07249618 A	8/26/95	Japan			Abstract	
		08242006 A	8/17/98	Japan			Abstract	
		S60-43485	3/8/85	Japan (Patent Disclosure)			X	
		H 02-155225	6/14/90	Japan (Patent Disclosure)			X	
		H3-185817	8/13/91	Japan (Patent Disclosure)			X	
		H3-187215	8/15/91	Japan (Patent Disclosure)			X	
		H3-91239	4/16/91	Japan (Patent Disclosure)			X	
		H5-62911	3/12/93	Japan (Patent Disclosure)			X	

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	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. ASME328A	APPLICATION NO. 10/074,633
	APPLICANT Michael A. Todd			
	FILING DATE February 11, 2002		GROUP 2812	

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
LP ↓ ✓	1.	4,966,861	10/30/90	Mieno et al.	437	99	
	2.	5,110,757	05/05/92	Arst et al.	437	89	
	3.	6,159,828	12/12/00	Ping et al.	438	486	
	4.	6,171,662 B1	01/09/01	Nakao	427	595	
	5.	6,197,669 B1	03/06/01	Twu et al.	438	585	
	6.	6,235,568 B1	05/22/01	Murthy et al.	438	231	

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
LP ↓ ✓	7.	Van Zant, Peter, "Microchip Fabrication," 4 <sup>th</sup> Ed., McGraw Hill, New York, (2000), pp. 364-365
	8.	Van Zant, Peter, "Microchip Fabrication," 4 <sup>th</sup> Ed., McGraw Hill, New York, (2000), p 380-382
	9.	Van Zant, Peter, "Microchip Fabrication," 4 <sup>th</sup> Ed., McGraw Hill, New York, (2000), pp. 385
	10.	Van Zant, Peter, "Microchip Fabrication," 4 <sup>th</sup> Ed., McGraw Hill, New York, (2000), pp. 522-526

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